

Non-contact, high-accuracy measurement system

Laser Scan Micrometer LSM-6902H







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Features

- The best repeatability available in the 25mm/1" class.
- The ultra-precise scanning motor enables the highest measurement accuracy.
- Thanks to excellent linearity, an accuracy of $\pm 0.5 \mu m$ over the entire measuring range and a higher accuracy of $\pm (0.3+0.1 \Delta D) \mu m$ over a narrow range are guaranteed.
- An excellent option for measuring pin gages or plug gages.

Specifications

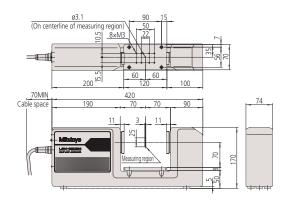


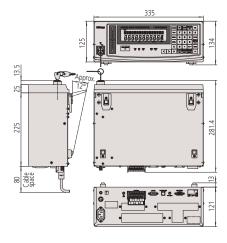
	LASER 2 レーザクラス 2	***			
1.3 mW(peak) 650 nm Semiconductor Laser Scanning Laser 6-93 µs FN/IFC60825-1:2014 JIS C 6802:2014					

Set Order No.		544-499A(mm/inch)			
Applicable standards			IEC · FDA		
Measuring unit			Display unit		
Measuring range		0.1 to 25mm (0.004 - 1.0 in)	Display	16-digit plus 11-digit fluorescent display, and guide message LED	
Resolution		0.01 to 10µm (selectable) (0.000001 - 0.0005 in)	Segment	1 to 7 (1 to 3, transparent) or 1 to 255 edges	
	1	±0.045µm (±0.0000018 in) (ø25mm)	Averaging times	Arithmetic average: 1 to 2048 scans. Moving average: 32 to 2048 scans.	
Repeatability*1		±0.03µm (±0.0000012 in) (ø10mm)	Judgment	Selection from "target value + tolerance", "lower tolerance + upper tolerance", or "7 classes multilimit tolerance zone".	
	_		Measurement mode	Standby, Single measurement, Continuous measurement	
Accuracy* ² (20°C)	Whole range	±0.5µm (±0.000020 in)	Statistical analysis	Maximum, Minimum, Max–Min, Average, Dispersion, (S.D)	
	Narrow range	±(0.3+0.1 ΔD) [D:mm]μm	External dimensions	335(W)×134(H)×250(D)mm	
		±(.000012+.0001 △D) [D:inch]*5	Power supply	100 to 240VAC ±10% 35W 50/60Hz	
Movement error*3		±0.5µm (±.000020")	Standard output	RS-232C, Analog I/O	
Measuring region*4		±1.5mm×25mm (±0.006×1.0 in)	Optional output	Digimatic code output unit (2-ch), 2nd I/O analog I/F, BCD I/F	
Scanning rate		1600 scans/s	Operating environment	0 to 40°C, RH 35 to 85% (non-condensing)	
				Nominal setting, sample setting, suppression of unnecessary digits, transparent object measurement, automatic measurement in edge mode, output timer, abnormal data elimination, SHL change, group judgment,	
Laser wavelength		650nm (visible)	Others		
Laser scanning speed		112m/s		simultaneous measurement, statistical processing, mastering, buzzer	
Operating environment	Temperature	0 to 40°C		function, automatic workpiece detection (dimension/position), zero-set/offset Note: In the case of dual measuring-unit connection, extra-fine line measurement and some of the communication commands are not available.	
	Humidity	RH 35 to 85% (non-condensing)			
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^{*1:} At the 2 σ level in the case where ø25mm and ø10mm diameters are measured using a measurement time of 1.28 seconds (2048 scans on average)
*2: The value at the center of the measuring range

Dimensions





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Form Measurement

Optical Measuri

Sensor System

Test Equipment

Digital Scale and DRO Systems

Small Tool Instruments and Data Management

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^{*3:} The additional error (in outside diameter) caused by workpiece movement within the measuring envelope during the measuring cycle

*4: Length along optical axis x Scanning length (Measuring range)

^{*5:} ΔD is the difference in outside diameter between the master gage and workpiece.